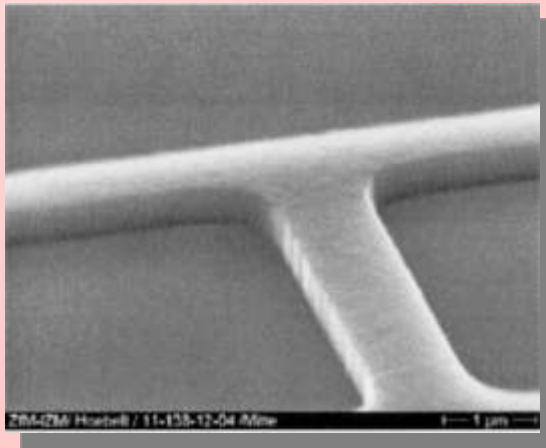


## Presentation FHR RIE 200

HKUST Tender TN 073(05/06)

*A versatile RIE system with manual loading  
for R&D and production with process  
guarantee !*



## Features:

- substrate electrode on rf potential, 1 wafer 200 mm, 1 wafer 150 mm, 7 wafers 2" diameter
- shielded electrode with thermostat system
- optimised gas shower head
- 13,56 MHz RF with automatic matching
- ICP source MaPE ICPC 200
- modular gas cabinet
- automatic control by PLC
- remote diagnostics
- open & modular design for upgrades

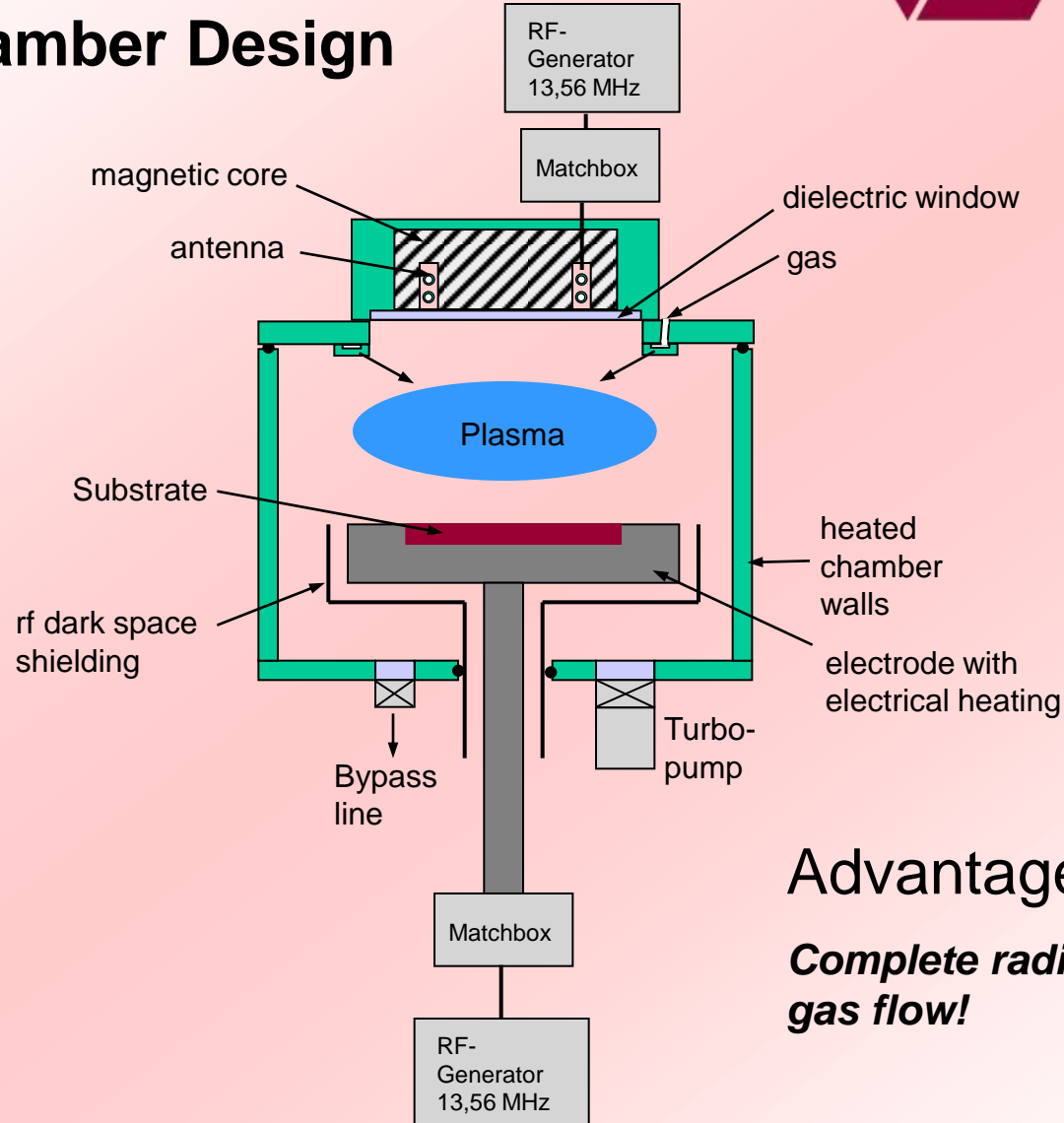


## Options:

- ICP source MAPE ICPR 200 (patented)
- Helium thermal coupling of substrate
- load lock system for automatically loading
- optical emission spectrometer (OES) for process control
- pulsed/ switched rf system
- exhaust gas treatment
- adjustable electrode distance



## Basic Chamber Design



Advantage:

***Complete radial symmetrical gas flow!***

## RIE - ICP Reactor

magnetic enhanced inductive coupled plasma



## MAPE-ICPR 200

(licensed by EC)



## RIE - ICP 200 Reactor

**advantages compared to standard RIE:**

- higher etching rates achievable
- independent control of chemical and physical component
  - better controllability of process in regard to:
    - etching profile,
    - etching rate
    - selectivity to resist and underlying materials



**advantage of MAPE-ICP to competitors:**

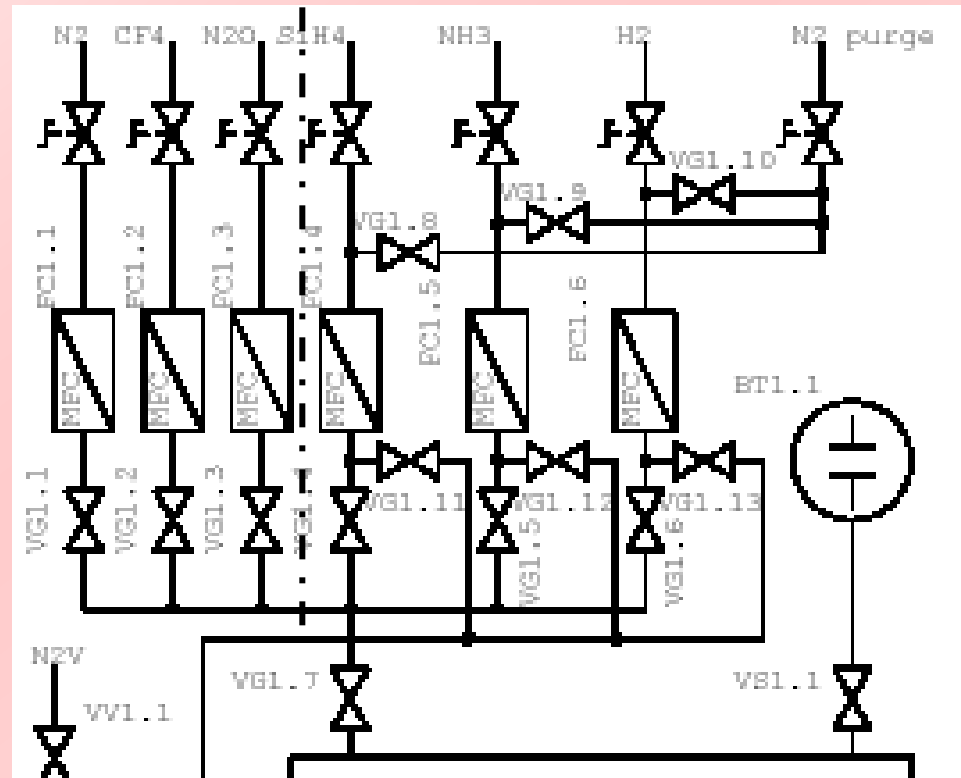
- decoupling of ICP antenna from process chamber
- higher uniformity and efficiency due to magnetic core assembly

**disadvantage: higher investment costs**

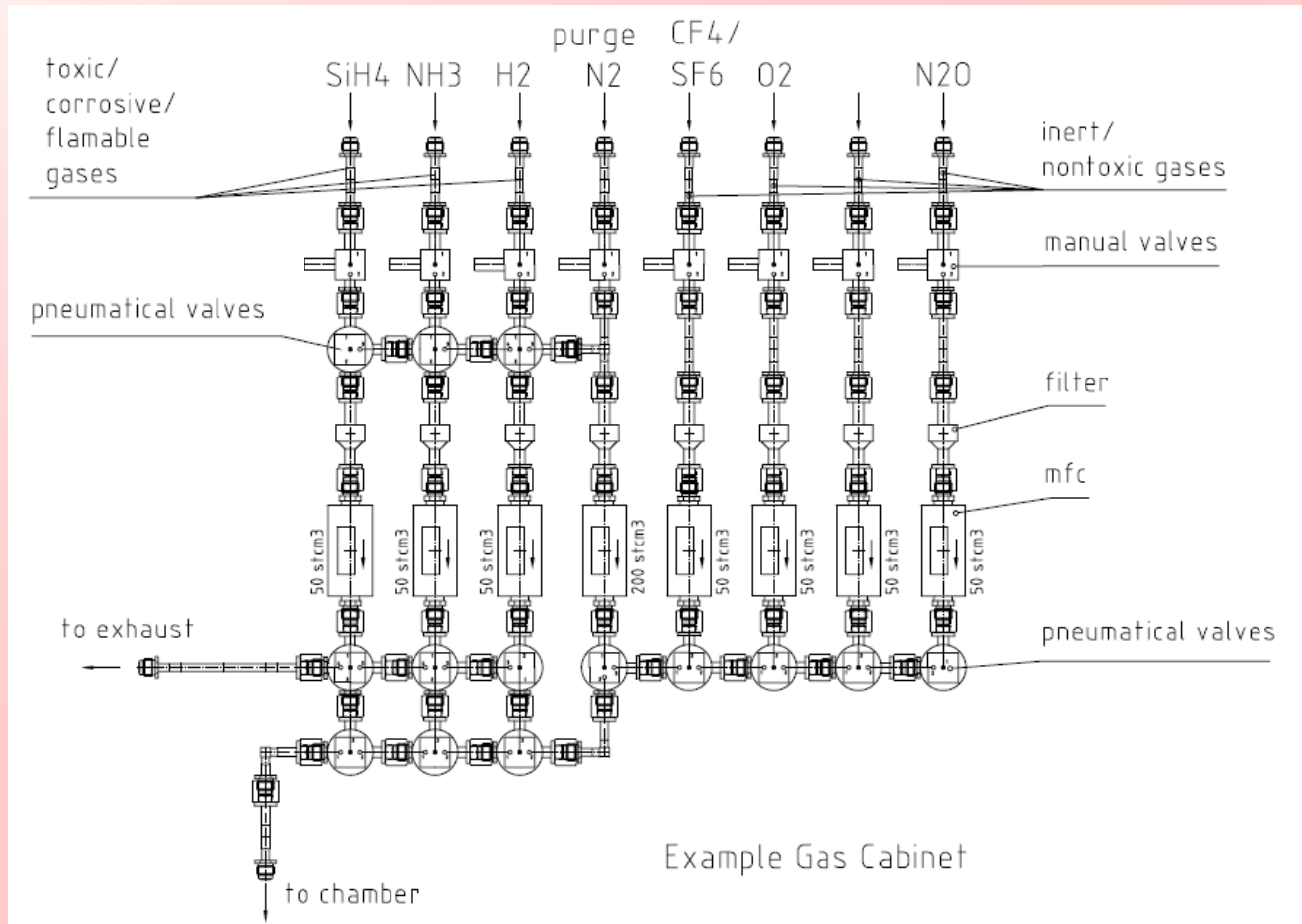
## Gas Cabinet Design

a) normal gases

b) corrosive, flammable, toxic gases include purge line !

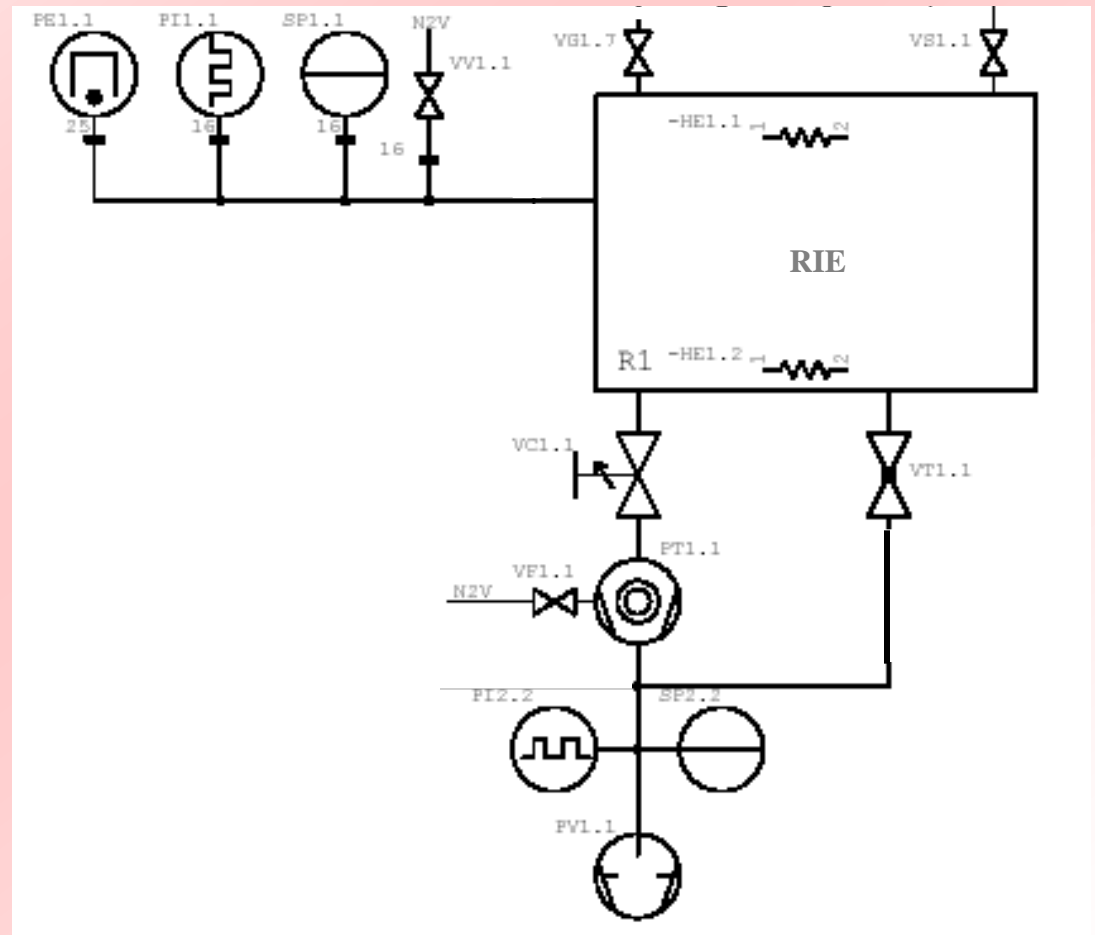


## Gas Lines Layout



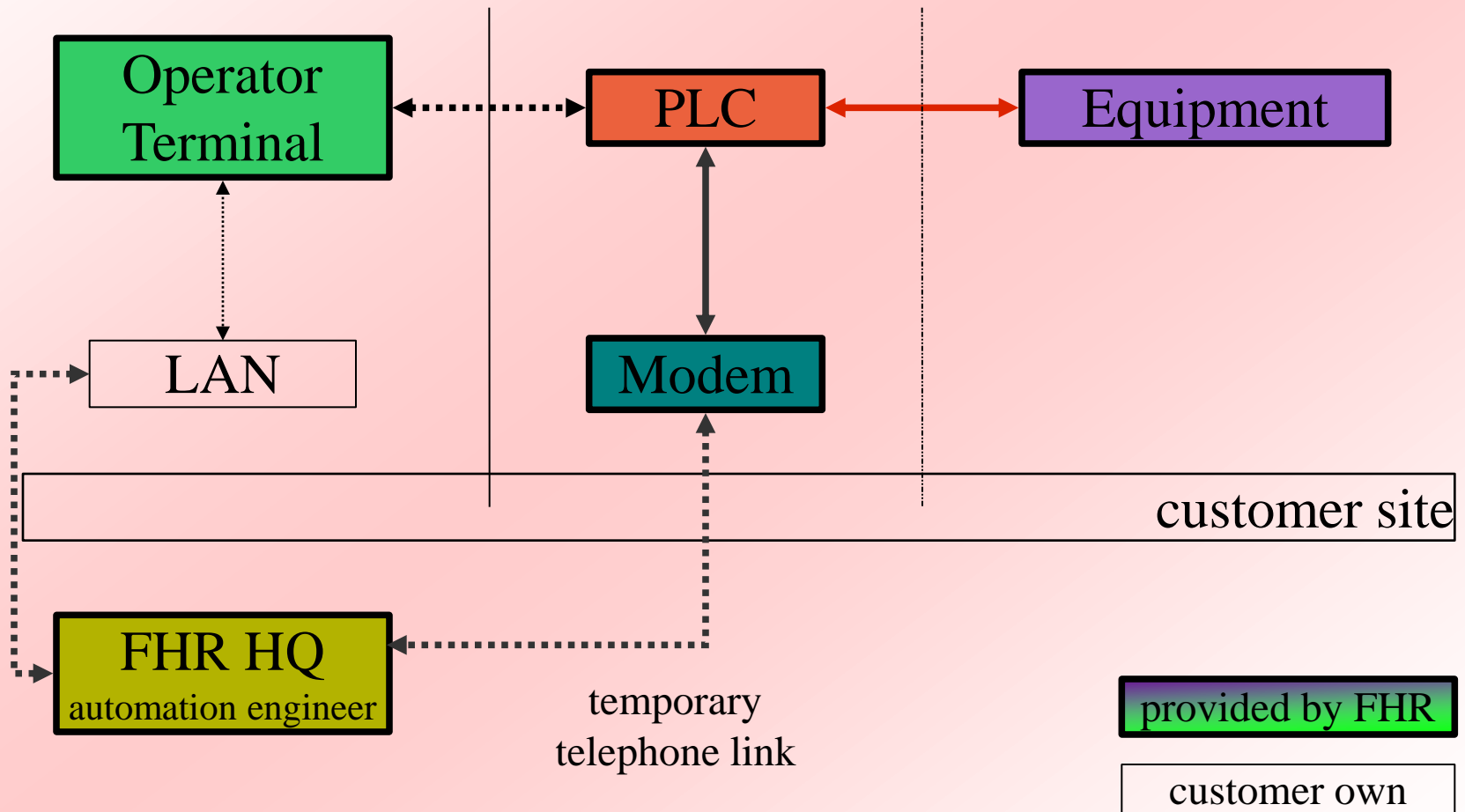
## Pump System

- powerful vacuum system by Roots/rotary pump combination; turbo pump also included! (UNAXIS group)
- full range gauges
- process gauge by capacitance manometer
- (MKS)



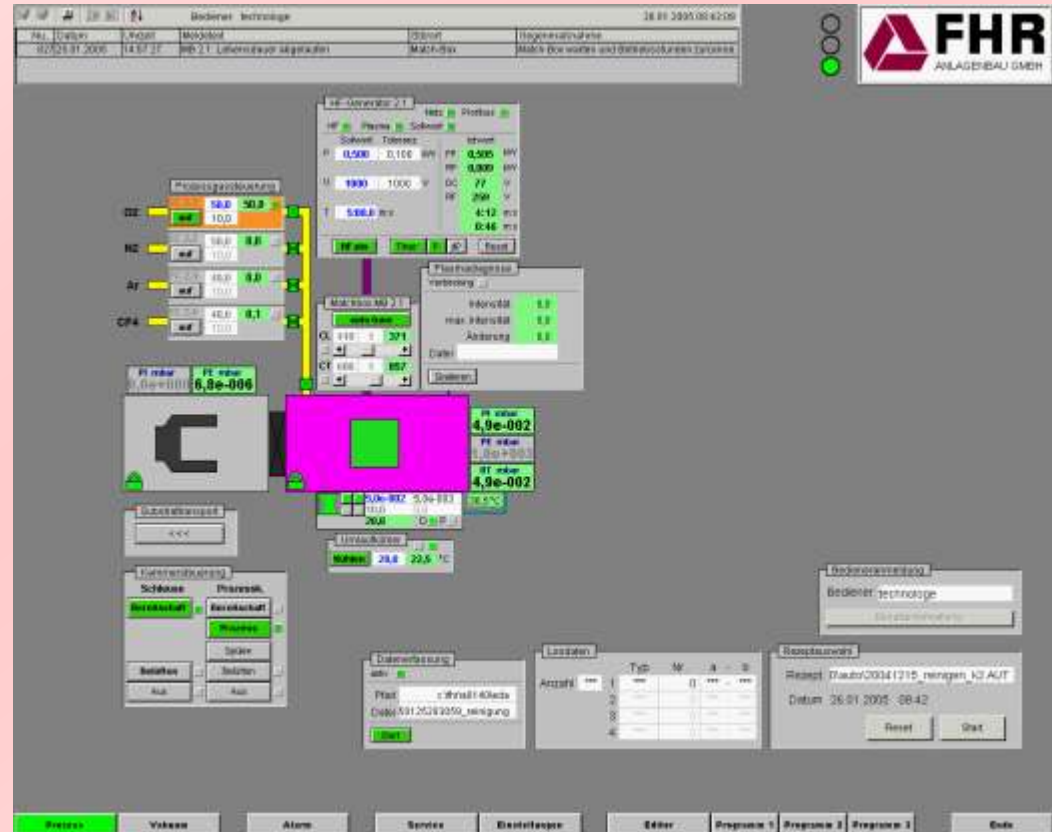
## Control System

Hardware: SIEMENS Simatic S7 PLC ( world wide PLC standard!)



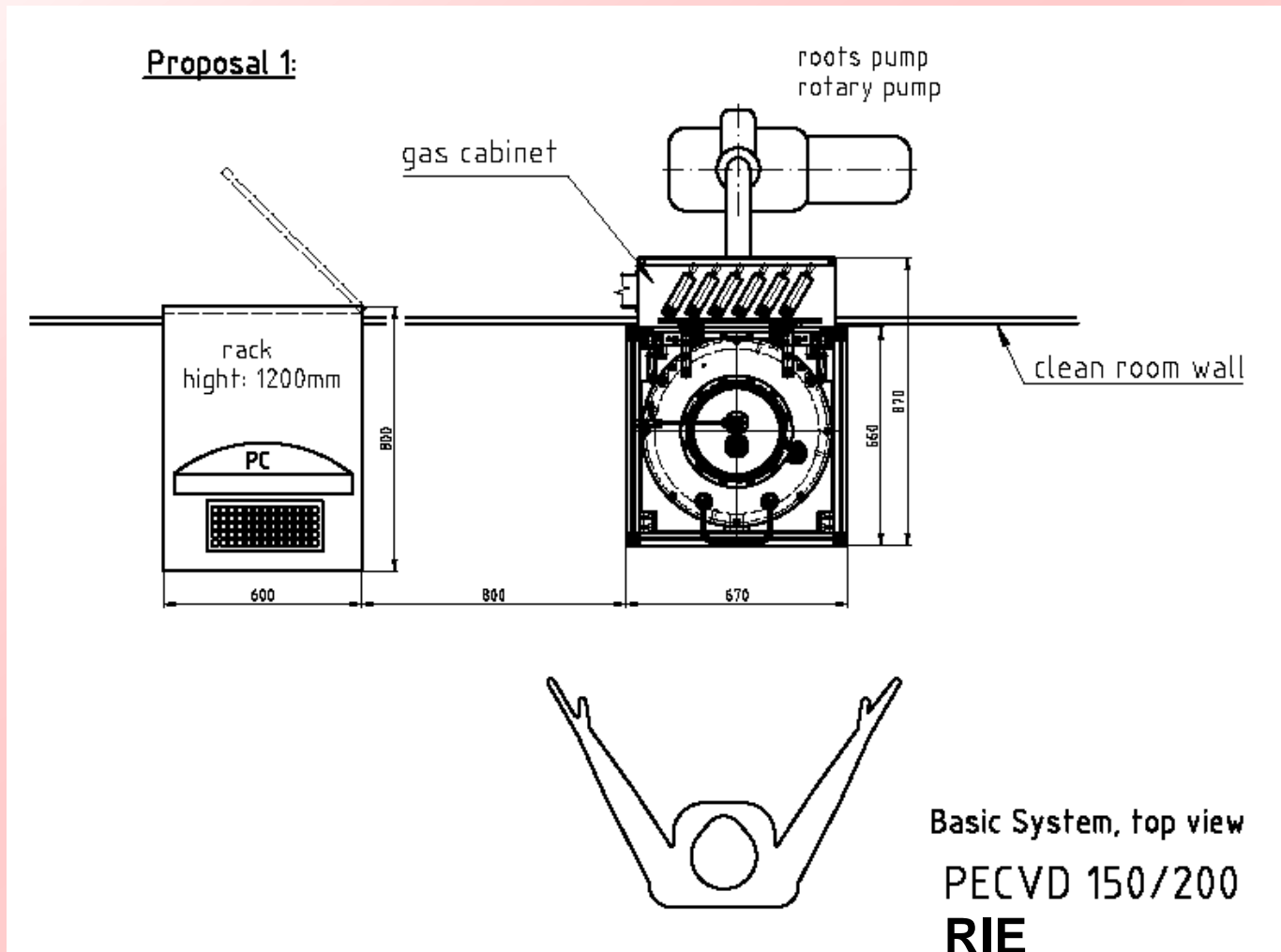
## Operator Terminal

- Windows XP/NT based operation system
- complete visualisation by SIEMENS WINCC
- different operating levels for maintenance, r&d, production
- easy programming/editing of programs
- „unlimited“ number of recipes
- data logging
- selecting automatic or manual mode at any recipe point !



## Installation

- customised layout for clean room installation



## Installation – Facility Conditions

- **El. Power:** 3x 400V, max. 6kVa
- **Water:** 10 l/min, 4...6bar
- **Compressed Air:** ca. 6 bar, static
- **Exhaust:** NW 100, gas cabinet,
- NW 40, pumps ( Exhaust gas treatment not included, optional available)
- **Thermal load:** ca. 2 kW

## Process Guaranty

- etching rate: > 35 nm nm/min for  $\text{SiO}_2$   
> 50 nm nm/min for  $\text{SiO}_x$
- Uniformity: < +/- 5% on 6" wafer, wafer to wafer
- Repeatability: < +/- 3% on 6" wafer
- CD change : < 0,1  $\mu\text{m}$
- Film profile: > 88° (anisotropic)
- Min. feature: < 1  $\mu\text{m}$  (lines & space )
- Selectivity: 3 to 5:1 to photo resist for  $\text{SiO}_2$   
1,5 to 3:1 to photo resist for  $\text{SiO}_x$

## Supported Processes by FHR

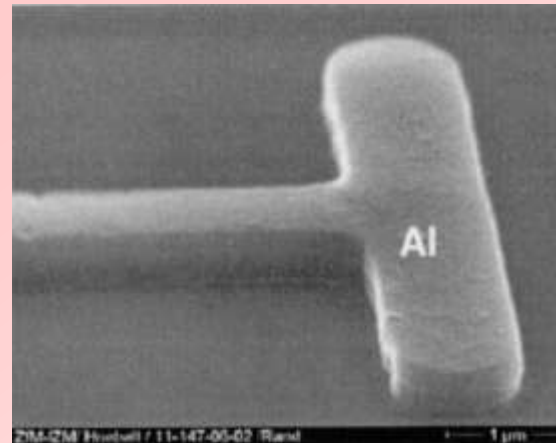
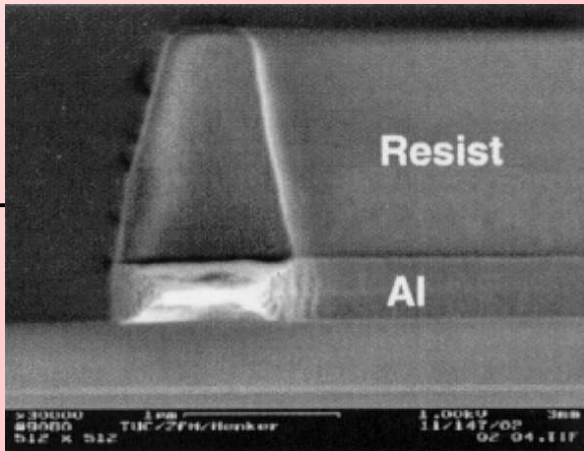
RIE of metals: Al, Cr,

RIE/PE of semiconductors: Si, GaAs, a-Si

RIE/PE of dielectrics:  $\text{SiO}_2$ ,  $\text{SiO}_x$ ,  $\text{Si}_3\text{N}_4$ ,  $\text{SiO}_x\text{N}_y$

Resist - Stripping

*Actual project: deep RIE of  $\text{SiO}_x$  for MEMS applications*



1 µm Al structure etched with  
50 nm/min and  $\text{BCl}_3/\text{Cl}_2$   
FHR RIE 200 by ZfM,  
TU Chemnitz Germany

## Reference Projects

Technical University Chemnitz, ZfM, Dr. Bertz

RIE/PECVD 200 Cluster ICP !

Application:

MEMS, SiO<sub>2</sub>, SiN<sub>x</sub> dep. DLC

SiO<sub>2</sub>, SiN<sub>x</sub>, Al, Cr etching



## Reference Projects

IFW Dresden, Leibnitz Institutes of Germany, Dr. Mönch

RIE/PECVD 100 Cluster

(2 process chambers, 1x ICP)

Application: Sensors, MEMS

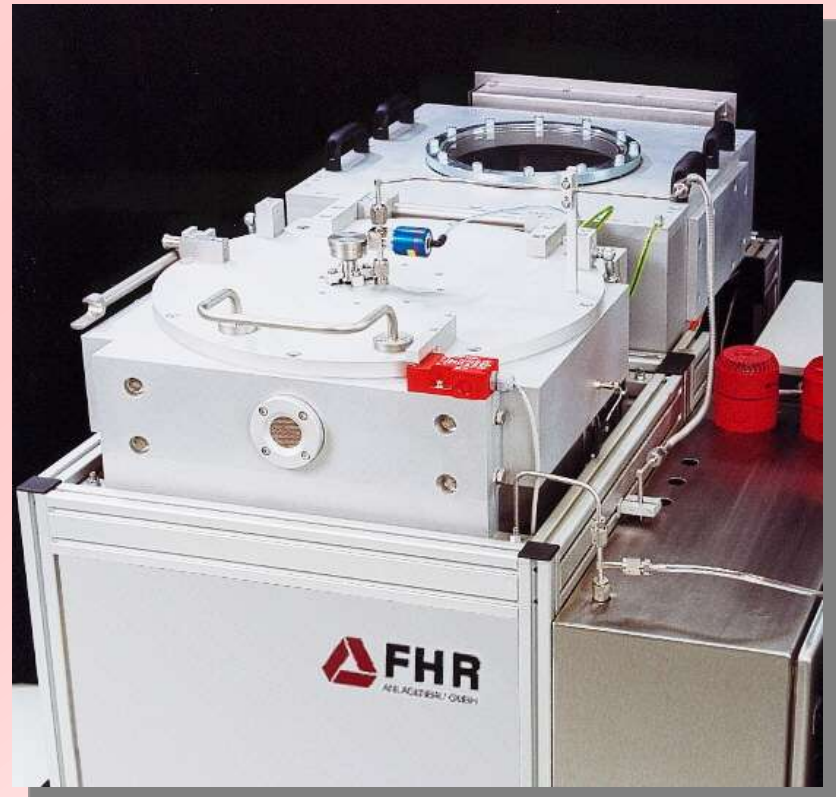
Deposition:

SiO<sub>2</sub>, SiN<sub>x</sub> dep. DLC

Eposition:

SiO<sub>2</sub>, SiN<sub>x</sub>,

Pt etching



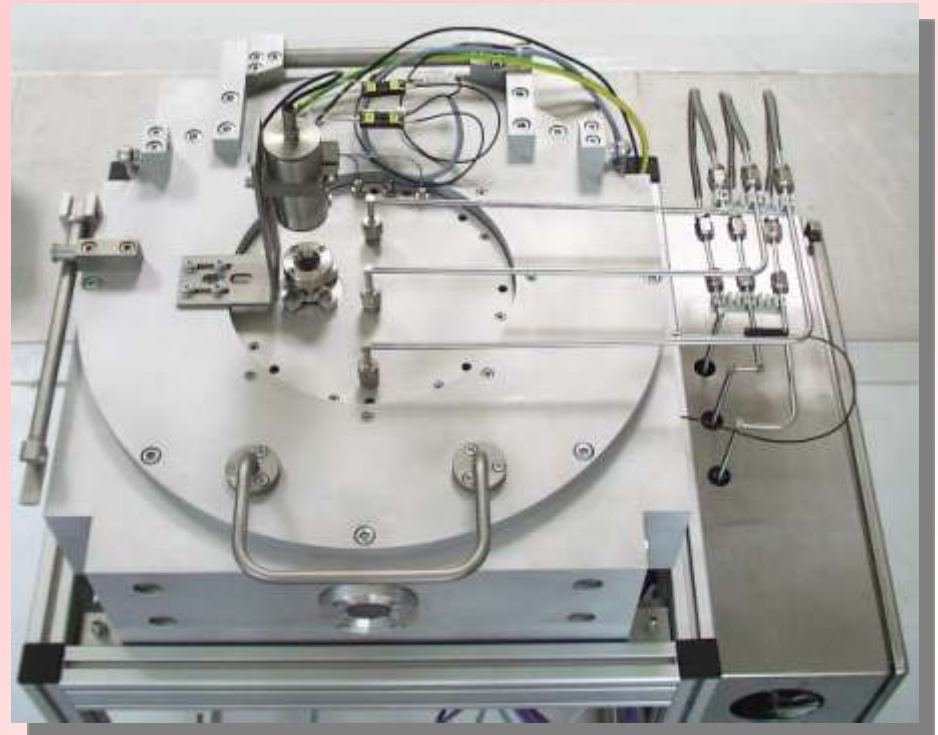
## Reference Projects

FAP Dresden, Dr. Schade

PECVD 200

Application: Sensors, Solar Cell

SiO<sub>2</sub>, SiN<sub>x</sub> dep. DLC, Poly-Si



# FHR RIE-ICP 200



## Reference Projects

E+E Elektronik, Hilbersdorf, Austria, Dr. Hilber

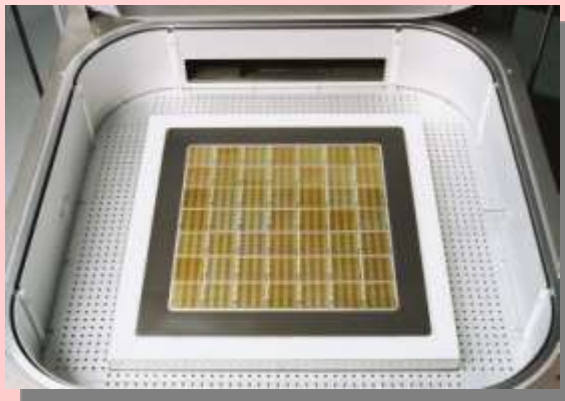
RIE 400 SQ

Application: Sensors,

SiNx Etching

Project for SiNx PECVD

In process



## Reference Projects

7 more systems stand alone & combined cluster in different configurations : PECVD ; RIE, Sputtering

100 ...200 mm wafer

In Germany, Italy, Sweden, Israel ( no detail information allowed)

Application: Sensors, MEMS,  
Compound Semiconductors



# FHR RIE-ICP 200

